X-ray and Neutron Scattering from Crystalline Surfaces and Interfaces

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Buried Interface Structure to understand the growth and function of materials



http://www.tyndall.ie/research/electronic-theory-group/thin_film_simulation.html

Crystal growth from a vapor



Morphology → atomic scale mechanisms



Cu/Cu(001)

Zuo & Wendelken

Interplay between two regimes of Length Scales

- Interatomic distances
 →Structure, physics, chemistry → Mechanisms
- "Mesoscale" Nanoscale \rightarrow Morphology \rightarrow Mechanisms

Unique Advantages of X-ray Scattering:

• Atomic-scale structure at a buried interface

- Morphological structure at buried interfaces
- Subsurface phenomena Strains and defects near a surface
 Accurate statistics of distributions (eg. Island size distributions)

Neutrons: low intensity- limited to reflectivity
Soft Matter and Bio materials; H₂O & D₂O
Magnetic materials

Example: Rotation of graphene planes affect electronic properties



Morphology → atomic scale mechanisms



Objective

 An introduction to surface scattering techniques Build a conceptual framework

• Reciprocal Space is a large place: where do we look?

Scattering of X-rays and Neutrons: $k = \frac{2\pi}{k}$ Helmholtz Equation

X-rays

Neutrons

$$\nabla^2 \vec{E} + k^2 n^2 (\vec{r}) \vec{E} = 0$$

$$\nabla^2 \Psi + \frac{2m}{\hbar^2} \left[E - V(\vec{r}) \right] \Psi = 0$$

n(r)=<u>inhomogeneous</u> refractive index

Refractive Index for neutron:
$$n(\vec{r}) = \sqrt{1 - \frac{2m}{\hbar^2 k^2}} V(\vec{r}) = \sqrt{1 - \lambda^2 \rho_b(\vec{r})/\pi}$$

Scattering length density: $\rho_b(\vec{r}) \xrightarrow{monoatomic} \rho_N(\vec{r}) b$
number density: $b = \begin{cases} r_e f(Q) & x - rays \\ tabulated - neutrons \end{cases}$

One language for both x-rays and neutrons





- 1. Grazing angle reflectivity: strong scattering d>>interatomic distances Exact solution required. Neglect atomic positions: <u>homogeneous medium</u>
- 2. Bragg region: strong scattering; d~interatomic distances = a Exact solution required. Atomic positions needed. Similar to e⁻ band theory.
- Everywhere else: weak scattering
 Born approximation →simplification. Atomic positions required.

Grazing Angles: Refraction and Total Reflection

d>>a: consider homogenous medium

Use average refractive index:



$$Q_c^2 = 16\pi\rho_b$$

Total Reflection



Critical Angle for Total External Reflection:

$$\theta_c = \sqrt{2\delta} \qquad Q_c = \frac{4\pi}{\lambda} \theta_c$$

Beam does not transmit below θ_c



Transmission Amplitude



FIG. 1. Fresnel transmissivity $|T_i|^2$ as a function of α_i / α_c for a transparent medium and the real systems Fe₃Al and Pb.



Calculation of reflectivity



L.G. Parratt, Phys Rev 95, 359 (1954)



http://www.ncnr.nist.gov/reflpak/



Soft Matter: Neutron Reflectivity



Biophysical Journal Volume 95 November 2008 4845–4861

Magnetic Films: Neutron Reflectivity



S. Park, M. R. Fitzsimmons, X. Y. Dong, B. D. Schultz, and C. J. Palmstrøm, Phys Rev B 70 104406 (2004)

Vortices in Thin-Film Superconductors Studied by Spin-Polarized Neutron Reflectivity (SPNR)

S-W. Han, J.F. Ankner, H.Kaiser, P.F.Miceli, E.Paraoanu, L.H.Greene, PRB **59**, 14692 (1999)



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YBCO 600 nm Superconducting Film





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Differential Scattering Cross Section

Weak Scattering "Born Approximation" or "Kinematic Approximation"

$$\frac{d\sigma}{d\Omega} = P S(\vec{Q}) = P \left| A(\vec{Q}) \right|^2$$

P is the polarization factor (x-ray case) S(Q) is the structure factor A(Q) is the scattering amplitude f(Q) is the atomic form factor ρ_b is the scattering length density

Reflectivity:

$$R = \frac{1}{A_{inc}} \int d\Omega \frac{d\sigma}{d\Omega}$$

$$d\Omega = \frac{d^2 \vec{Q}_p}{k^2 \sin(\alpha_f)}$$



Born Approximation: simple sum over atomic positions

Sum over all atomic positions

$$A(\vec{Q}) = \int d^3 \vec{r} \ \rho_b(\vec{r}) e^{i\vec{Q}\cdot\vec{r}} = \sum_{\vec{r}} b_{\vec{r}} \ e^{i\vec{Q}\cdot\vec{r}}$$

 $b = r_e f(Q)$ for x-rays or tabulated for neutrons



General Case: non-specular scattering



- refraction of both beams internal wavevector transfer: \vec{Q}'
- transmission of both beams: T_i , T_f

Perpendicular to Surface: internal **Q**' and external **Q** are different

$$Q_{z} = k_{z}^{(f)} - k_{z}^{(i)} = (2\pi/\lambda) [\sin\alpha_{f} + \sin\alpha_{i}].$$
$$Q_{z}' = k_{z}^{(f)'} - k_{z}^{(i)'} = (2\pi/\lambda) [(\sin^{2}\alpha_{f} - 2\delta - 2i\beta)^{1/2} + (\sin^{2}\alpha_{i} - 2\delta - 2i\beta)^{1/2}].$$

Parallel to Surface: internal Q' and external Q are same



H. Dosch, B.W. Batterman and D. C. Wack, PRL 56, 1144 (1986)





A Six-Circle Diffractometer



H. You, J. Appl. Cryst. 32, 614-623 (1999)

UHV Growth and Analysis Chamber At Sector 6 at Advanced Photon Source

- UHV 10⁻¹⁰ Torr
 Evaporation/deposition
 Ion Sputtering
 LEED
 Auger
 Low Temp: 55K
 High Temp: 1500 °C
 - Load Lock/sample transfer

Liquid Surface Diffractometer



M. Schlossman et. al., Rev. Sci. Inst. 68, 4372 (1997)



David Vaknin, Ames Lab

The Effect of a Crystalline Boundary

What is a crystal truncation rod?

First consider:

• Large crystals; rough and irregular boundaries



G is a reciprocal lattice vector


By neglecting the lateral boundaries:

$$\sum_{\vec{R}_{p}} \sum_{\vec{R}'_{p}} e^{i\vec{Q}_{p} \cdot (\vec{R}_{p} - \vec{R}'_{p})} = N_{irr} \sum_{\vec{R}_{p}} e^{i\vec{Q}_{p} \cdot \vec{R}_{p}}$$

and
$$\sum_{\vec{R}_{p}} e^{i\vec{Q}_{p} \cdot \vec{R}_{p}} = \frac{(2\pi)^{2}}{s_{c}} \sum_{\vec{G}_{p}} \delta(\vec{Q}_{p} - \vec{G}_{p})$$

 N_{irr} = the number of irradiated atoms at the surface S_c = area per surface atom \vec{C}_c = area in plane regions at lettice we ster

$$G_p$$
 = an in-plane reciprocal lattice vector







Elliott et. al. PRB 54, 17938 (1996)





Specular Reflection from the Ag(111) Surface Correct Crystal Truncation Rod Scattering for Terrace Size



Elliott et. al. PRB **54**, 17938 (1996)

The Effect of a Rough Surface





In situ vapor deposition in UHV







Transverse Lineshape

Far regions of surface
$$R_p \rightarrow \infty$$

Uncorrelated heights
 $\left\langle e^{iQ_z \left(h\left(\vec{R}_p + \vec{R}'_p\right) - h\left(\vec{R}'_p\right)\right)} \right\rangle_{\vec{R}'_p} \rightarrow \left| \left\langle e^{iQ_z h} \right\rangle \right|^2$
Uncorrelated Roughness @ Large Distance Gives Bragg:
 $S_T^{Bragg} \left(\vec{Q}_p\right) = \frac{(2\pi)^2}{s_c} \delta\left(\vec{Q}_p - \vec{G}_p\right) \left| \left\langle e^{iQ_z h} \right\rangle \right|^2$

Short-Range Correlations Give Diffuse Scattering:

$$S_T^{Diffuse}\left(\vec{Q}_p\right) = \sum_{\vec{R}_p} e^{i\vec{Q}_p \cdot \vec{R}_p} \left\{ \left\langle e^{iQ_z \left(h\left(\vec{R}_p + \vec{R}'_p\right) - h\left(\vec{R}'_p\right)\right)} \right\rangle_{\vec{R}'_p} - \left| \left\langle e^{iQ_z h} \right\rangle \right|^2 \right\}$$

Two Component Line Shape: Bragg + Diffuse $S_T(\vec{Q}_p) = S_T^{Bragg}(\vec{Q}_p) + S_T^{Diffuse}(\vec{Q}_p)$

- Bragg due to laterally uncorrelated disorder at long distances
- Diffuse due to short-range correlations



Layer-by-layer growth

- Specular Bragg Rod: intensity changes with roughness
- Strong inter-island correlations seen in the diffuse



Attenuation of the Bragg Rod and Surface Roughness

If height fluctuations are Gaussian: σ is rms roughness



- Binomial distribution (limits to a Gaussian for large roughness)
- Preserves translational symmetry in the roughness

Physica B 221, 65 (1996)

- Sharper interface (real space) gives broader scattering
- Gaussian roughness does not give translational symmetry





Bragg is narrow:

it samples laterally uncorrelated roughness at long distances

$$S^{Bragg}\left(\vec{Q}\right) \propto \frac{\left|b\right|^2}{\left|1-e^{iQ_z c}\right|^2} e^{-4\frac{\sigma^2}{c^2}\sin^2\left(\frac{Q_z c}{2}\right)}$$

Transversely-integrated scattering shows no effect of roughness:

(for 1 interface)

$$\iint d^2 Q_p S\left(\vec{Q}\right) \propto \frac{\left|b\right|^2}{\left|1 - e^{iQ_z c}\right|^2}$$

In practice, at every Q_z the diffuse must be subtracted from the total intensity to get the Bragg rod intensity:



What do we expect from a Thin Film?

1st let's recall Young's slit interference...

Recall...

N-Slit Interference and Diffraction Gratings



Principle maxima

d sin $\theta = m\lambda$



"5-slit" interference of x-rays from 5 layers of atoms



Miceli et al., Appl. Phys. Lett. 62, 2060 (1992)





Specular Reflectivity: 0.3ML Ag/Si(111)7x7





Specular Reflectivity: 0.9ML Ag/Si(111)7x7



Specular reflectivity cannot easily distinguish between these two cases:





Quantum-Size-Effects: Pb Nanocyrstals on Si(111)7x7

Height Selection: "Magic" crystal heights Quantum Mechanics Influences Nanocrystal Growth

Discoveries:

- anomalously (10⁴) fast kinetics
- Non-classical coarsening
- Unusual behavior: fast growth => most stable structures



C. A. Jeffrey et al., PRL 96, 106105 (2006)

Electrons in a "box"



F. K. Schulte, Surf. Sci. **55**, 427 (1976) P. J. Feibelman, PRB **27**, 1991 (1983)

physchem.ox.ac.uk



Rain Drops On Your Winshield

laist.com greeneurope.org





Classical Coarsening: Ostwald Ripening





Long time: independent / of initial conditions





Relaxation time depends only on the initial density

Pb Nanocrystal Coarsening

...does **not** conform to the classical picture!



Reciprocal Space is Superb for Obtaining Good Statistics of Distributions


Summary

Materials research problems require information on a broad range of length scales, from atomic to mesoscale

Scattering from surfaces involves many different types of measurements:

Reflectivity, Rods, Grazing Incidence
Diffraction, Diffuse Scattering

Unique ability of x-rays: surface and subsurface structure simultaneously